2025 Bahar - EEM/EEE228 final sınavına dahil konuların listesi
(Kitap: “Microelectronic Circuits, 7th ed. (2014), A.S. Sedra, K.C. Smith”)

Chapter 4 Diodes

4.1 The Ideal Diode (hepsi)
4.2 Terminal Characteristics of Junction Diodes (hepsi)
4.3 Modeling the Diode Forward Characteristic (hepsi)
4.4 Operation in the Reverse Breakdown Region—Zener Diodes (hepsi)
4.5 Rectifier Circuits (kitap sayfa 218’e kadar)

Chapter 5 MOS Field-Effect Transistors (MOSFETs)

5.1 Device Structure and Physical Operation (Example 5.1’in kitap sayfa 261’deki sonuna kadar)

5.2 Current–Voltage Characteristics (aşağıdakiler hariç hepsi)

- 5.2.4 Finite Output Resistance in Saturation
- 5.2.5 Characteristics of the p-Channel MOSFET

5.3 MOSFET Circuits at DC (Example 5.5’in kitap sayfa 281’deki sonuna kadar)

Chapter 6 Bipolar Junction Transistors (BJTs)

6.1 Device Structure and Physical Operation (aşağıdakiler hariç hepsi)

- Minority-Carrier Distribution
- 6.1.3 Structure of Actual Transistors
- 6.1.5 The pnp Transistor

6.2 Current–Voltage Characteristics (aşağıdaki hariç hepsi)

- The Collector–Base Reverse Current (I_{CBO})

6.3 BJT Circuits at DC (Example 6.11’in kitap sayfa 349’daki sonuna kadar)